WHAT WE CLAIM IS:

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1. A semiconductor light-emitting device, comprising a substrate and a first electrically conductive type semiconductor layer or layers, an active layer and a second electrically conductive type semiconductor layer or layers stacked on a major surface of the substrate, wherein:

a major surface of the first electrically conductive type semiconductor layer is provided with a recess, and

the first electrically conductive type semiconductor layer is contiguous to the active layer formed within and without said recess in two or more plane orientations.

- 2. The semiconductor light-emitting device according to claim 1, wherein said semiconductor layers and said active layer are each a gallium nitride semiconductor layer.
- 3. The semiconductor light-emitting device according to claim 1, wherein the first electrically conductive type is an n-type and the second electrically conductive type is a p-type.
- 4. The semiconductor light-emitting device according to claim 1, wherein said active layer has a quantum well structure including a well layer comprising an In-containing gallium nitride semiconductor.
- 25 5. The semiconductor light-emitting device according to claim 1, wherein at least one of surfaces of the first electrically conductive type semiconductor layer contiguous to the active layer defines the major surface

of the first electrically conductive type semiconductor layer.

- 6. The semiconductor light-emitting device according to claim 1, wherein at least one of surfaces of the first electrically conductive semiconductor layer contiguous to the active layer is a surface vertical to the major surface of the first electrically conductive type semiconductor layer.
- 7. The semiconductor light-emitting device

 10 according to claim 1, wherein the major surface of the first electrically conductive type semiconductor layer is a C plane of the gallium nitride semiconductor.
 - 8. The semiconductor light-emitting device according to claim 6, wherein the surface vertical to the major surface of the first electrically conductive type semiconductor layer is an A or M plane of the gallium nitride semiconductor.

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- 9. The semiconductor light-emitting device according to claim 8, wherein said active layer comprises 20 a plurality of continuous M or A planes that make an angle of 30°, 60°, 90°, 120°, 150°, 210°, 240°, 270°, 300° or 330°, as viewed from an upper surface of the first electrically conductive type semiconductor layer having a recess.
- 25 10. The semiconductor light-emitting device according to claim 8, wherein said active layer has a striped M or A plane, as viewed from an upper surface of

the first electrically conductive type semiconductor layer having a recess.

11. The semiconductor light-emitting device according to claim 1, wherein said active layer comes in contact with the second electrically conductive type semiconductor layer in a plane orientation contiguous to the first electrically conductive type semiconductor layer.

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- according to claim 1, wherein a first electrode is formed
 on at least a part of a surface of the first electrically
 conductive type semiconductor layer, said surface being
 exposed by etching of the second electrically conductive
 type semiconductor layer and said active layer, and a
 second electrode is formed on at least a part of a surface
 of the second electrically conductive type semiconductor
 layer.
 - 13. The semiconductor light-emitting device according to claim 1, wherein said active layer emits light components having two or more different major peak wavelengths, in which said light components are mixed to show a color.
 - 14. A semiconductor light-emitting device fabrication process, comprising:
- a first step of forming a first electrically

 25 conductive type semiconductor layer on a growth substrate,
 - a second step that is carried out after the first step to form a recess in the first electrically conductive type semiconductor layer by etching,

a third step that is carried out after the second step to form an active layer contiguously to two or more different plane orientations of the first electrically conductive type semiconductor layer, and

a fourth step of forming a second electrically conductive type semiconductor layer.

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- 15. The semiconductor light-emitting device fabrication process according to claim 14, wherein said semiconductor layers and said active layer are each a gallium nitride semiconductor layer.
- 16. The semiconductor light-emitting device fabrication process according to claim 15, wherein said growth substrate in the first step is a sapphire substrate whose major surface is defined by a C plane, and the first electrically conductive type semiconductor layer is grown on the C plane of said substrate.
- 17. The semiconductor light-emitting device fabrication process according to claim 15, wherein said recess in the second step is formed by exposing an M plane or/and an A plane of the gallium nitride semiconductor layer.
- 18. The semiconductor light-emitting device fabrication process according to claim 15, wherein said active layer has a quantum well structure including a well layer comprising an In-containing gallium nitride semiconductor layer.